

# IEEE Eleventh Workshop on RTL and High Level Testing (WRTL'T'10)

December 5-6, 2010, Shanghai SHERATON Hotel, Shanghai, P. R. China

## CALL FOR PAPERS



### Sponsored by

**IEEE Computer Society Test Technology Technical Council**

### In cooperation with

**Shanghai Normal University**

**Tongji University**

**Tsing Hua University**

**National Natural Science Foundation of China (NSFC)**

**China Computer Federation (CCF), Committee of Fault-tolerant Computing (CFTC)**



### Scope

The purpose of this workshop is to bring researchers and practitioners on LSI testing from all over the world together to exchange ideas and experiences on register transfer level (RTL) and high level testing.

The tenth workshop on RTL and high level testing (WRTL'T'10) will be hold in conjunction with the 19<sup>th</sup> Asian Test Symposium (ATS'10) in Shanghai, China. We hope and expect this workshop provides an ideal forum for frank discussion on this important topic for the future system-on-a-chip (SoC) devices.

Areas of interest includes but not limited to:

- Functional fault modeling
- RTL ATPG
- RTL DFT
- RTL BIST
- Relationship between RTL and gate level testing
- Design verification
- High level test bench generation
- SoC testing
- High level approach for testing
- Microprocessor testing

### Paper Submissions

Authors are invited to submit paper proposals for presentation at the workshop. The proposal may be an extended summary (1,000 words) or a full paper and should includes: title, full name and affiliation of all authors, 100 words abstract and 5 keywords. The full mailing address, phone, fax and email address of the corresponding author should be specified. All submissions must be made electronically in PDF format. Please visit our web site (<http://wrtl't10.shnu.edu.cn>) for full submission instructions and updated information on the workshop.

Papers will be reviewed internationally and selected based on their originality, significance, relevance, and clarity of presentation.

The submissions will be considered evidence that upon acceptance the author(s) will prepare the final manuscript on time for inclusion in the digests and will present the paper at the workshop.

### Important Dates

**Submission deadline: July 7, 2010**

**Notification of acceptance: August 31, 2010**

**Camera-ready copy: September 30, 2010**

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### Program Committee

#### To be invited

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